











TS5A9411

SCDS241B-MAY 2008-REVISED DECEMBER 2016

TS5A9411 10- Ω 1:2 SPDT Analog Switch Single-Channel 2:1 Multiplexer and Demultiplexer

Features

- Specified Break-Before-Make Switching
- Low ON-State Resistance (10- Ω Maximum at $V_{CC} = 5 \text{ V}$)
- Low Power Consumption
- TTL- and CMOS-Compatible Control Input
- Low Input and Output Capacitance
- **Excellent ON-State Resistance Matching**
- Low Total Harmonic Distortion
- 2.25-V to 5.5-V Single-Supply Operation
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- ESD Performance Tested Per JESD 22
 - 2000-V Human-Body Model (A114-B, Class II)
 - 1000-V Charged-Device Model (C101)
- Control Inputs Are 5.5-V Tolerant

2 Applications

- Cell Phones
- Communication Systems
- Portable Test Equipment
- **Battery Operated Systems**
- Sample-and-Hold Circuits

3 Description

The TS5A9411 device is a bidirectional, single-pole double-throw (SPDT) analog switch that is designed to operate from 2.25 V to 5.5 V. The device offers low ON-state resistance, low leakage, and low power with a break-before-make feature. These features make this device suitable for portable and battery-powered applications.

Device Information⁽¹⁾

PART NUMBER	PACKAGE	BODY SIZE (NOM)		
TS5A9411	SOT (6)	2.00 mm × 1.25 mm		

(1) For all available packages, see the orderable addendum at the end of the data sheet.

Simplified Schematic

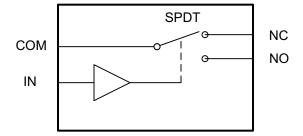




Table of Contents

1	Features 1	8.3 Feature Description	13
2	Applications 1	8.4 Device Functional Modes	12
3	Description 1	9 Application and Implementation	13
4	Revision History2	9.1 Application Information	13
5	Pin Configuration and Functions3	9.2 Typical Application	13
6	Specifications	10 Power Supply Recommendations	14
Ŭ	6.1 Absolute Maximum Ratings	11 Layout	14
	6.2 ESD Ratings	11.1 Layout Guidelines	14
	6.3 Recommended Operating Conditions	11.2 Layout Example	14
	6.4 Thermal Information	12 Device and Documentation Support	18
	6.5 Electrical Characteristics: 5-V Supply4	12.1 Device Support	18
	6.6 Electrical Characteristics: 3-V Supply 5	12.2 Documentation Support	10
	6.7 Electrical Characteristics: 2.5-V Supply 6	12.3 Receiving Notification of Documentation	Updates 16
	6.8 Typical Characteristics	12.4 Community Resources	10
7	Parameter Measurement Information 8	12.5 Trademarks	10
8	Detailed Description 12	12.6 Electrostatic Discharge Caution	10
-	8.1 Overview	12.7 Glossary	16
	8.2 Functional Block Diagram	13 Mechanical, Packaging, and Orderable Information	

4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

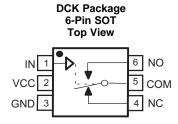
Changes from Revision A (July 2008) to Revision B

Page

•	Added Device Information table, Pin Configuration and Functions section, Specifications section, ESD Ratings table, Recommended Operating Conditions table, Detailed Description section, Application and Implementation section, Power Supply Recommendations section, Layout section, Device and Documentation Support section, and Mechanical, Packaging, and Orderable Information section	1
•	Deleted Ordering Information table; see Package Option Addendum at the end of the data sheet	1
•	Deleted Summary of Characteristics table	. 1
•	Moved ON-state switch current and ON-state peak switch current From: Absolute Maximum Ratings table To: Recommended Operating Conditions table	4
•	Added Thermal Information table	. 4
•	Changed Package thermal impedance, R _{0JA} , value in <i>Thermal Information</i> table From: 259°C/W To: 346.7°C/W	4
•	Deleted Charge Injection vs V _{COM} graph from Typical Characteristics	7
•	Changed graph title From: OFF Isolation vs Crosstalk ($V_{CC} = 3 \text{ V}$) To: Crosstalk and Insertion Loss vs Frequency ($V_{CC} = 3 \text{ V}$) in <i>Typical Characteristics</i>	7
•	Changed V+ to V _{CC} and IN to V _{IN} on all images in <i>Parameter Measurement Information</i>	8



5 Pin Configuration and Functions



Pin Functions

PI	N	1/0	DESCRIPTION
NAME	NO.	1/0	DESCRIPTION
COM	5	I/O	Common signal path
GND	3		Digital ground
IN	1	I	Digital control input. High = COM connected to NO; Low = COM connected to NC.
NC	4	I/O	Normally closed signal path
NO	6	I/O	Normally open signal path
VCC	2	_	Power supply

6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)(2)

	MIN	MAX	UNIT
Supply voltage	-0.3	6	V
Analog voltage ⁽³⁾	-0.3	$V_{CC} + 0.3$	V
Digital input voltage	-0.5	V _{CC} + 0.3	V
Analog port diode current (V _{NC} , V _{NO} , V _{COM} < 0)	-50		mA
Digital input clamp current (V _I < 0)	-50		mA
Continuous current through VCC		100	mA
Continuous current through GND	-100		mA
Storage temperature, T _{stg}	-65	150	°C

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

			VALUE	UNIT
.,		Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	±2000	.,
V _(ESD) Elec	Electrostatic discharge	Charged-device model (CDM), per JEDEC specification JESD22-C101 (2)	±1000	V

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

⁽²⁾ All voltages are with respect to ground, unless otherwise specified.

⁽³⁾ This value is limited to 5.5 V (maximum).

⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
V_{CC}	Supply voltage		2.25	5.5	V
V_{NO}		NC	0	V_{CC}	
V _{NC}	Analog voltage	NO	0	V_{CC}	V
V_{COM}		СОМ	0	V_{CC}	
VI	Digital input voltage		0	5.5	V
	ON-state switch current (V _{NO} , V _{NC} , V _{COM} = 0 to V _{CC})		-50	50	mA
	ON-state peak switch current (V _{NO} ,	ON-state peak switch current $(V_{NO}, V_{NC}, V_{COM} = 0 \text{ to } V_{CC})^{(1)}$		200	mA

⁽¹⁾ Pulse at 1-ms duration < 10% duty cycle

6.4 Thermal Information

		TS5A9411			
	THERMAL METRIC ⁽¹⁾				
$R_{\theta JA}$	Junction-to-ambient thermal resistance	346.7	°C/W		
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	163.7	°C/W		
$R_{\theta JB}$	Junction-to-board thermal resistance	154.5	°C/W		
ΨЈТ	Junction-to-top characterization parameter	17.4	°C/W		
ΨЈВ	Junction-to-board characterization parameter	153.8	°C/W		

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

6.5 Electrical Characteristics: 5-V Supply

 $V_{CC} = 5 \text{ V}, T_A = 25^{\circ}\text{C}$ (unless otherwise noted)

	PARAMETER	TES	T CONDITIONS		MIN	TYP	MAX	UNIT
ANALOG	SWITCH			,				
_	ON state assistance	V_{NO} or $V_{NC} = 3 \text{ V}, V_{CC} = 4.5 \text{ V},$		T _A = 25°C		5.3	9	
r _{ON}	ON-state resistance	$I_{COM} = -10$ mA, Switch ON, see		-40°C ≤ T _A ≤ 85°C			10	Ω
A =	ON-state resistance match	V_{NO} or $V_{NC} = 3 \text{ V}, V_{CC} = 4.5 \text{ V},$		T _A = 25°C		0.03	0.3	Ω
Δr_{ON}	between channels	$I_{COM} = -10$ mA, Switch ON, see	e Figure 5	-40°C ≤ T _A ≤ 85°C			0.3	22
r _{ON(FLAT)}	ON-state resistance flatness	$0 \le (V_{NO} \text{ or } V_{NC}) \le V_{CC}, V_{CC} = C$ $I_{COM} = -10 \text{ mA}, \text{ Switch ON, see}$				2		Ω
I _{NC(OFF)} ,		V_{NC} or $V_{NO} = 1$ V and $V_{COM} = 1$		T _A = 25°C	-500		500	pA
I _{NO(OFF)}	NC, NO OFF leakage current		V_{NC} or V_{NO} = 4.5 V and V_{COM} = 1 V; V_{CC} = 5.5 V, Switch OFF, see Figure 6		-3		3	nA
I _{NC(ON)} ,			V_{NC} or $V_{NO} = 1$ V and $V_{COM} = 1$ V, or		-500		500	pА
I _{NO(ON)}	NC, NO ON leakage current	V_{NC} or V_{NO} = 4.5 V and V_{COM} = V_{CC} = 5.5 V, Switch ON, see F		-40°C ≤ T _A ≤ 85°C	-3		3	nA
	COM ON lookage current	V _{NC} or V _{NO} = Open, V _{COM} = 1 V	√ or 4.5 V,	T _A = 25°C	-500		500	pΑ
I _{COM(ON)}	COM ON leakage current	$V_{CC} = 5.5 \text{ V}$, Switch ON, see F	igure 7	-40°C ≤ T _A ≤ 85°C	-3		3	nΑ
DIGITAL I	INPUT (IN) ⁽¹⁾			,				
V _{IH}	Input logic high	-40°C ≤ T _A ≤ 85°C	$4.5 \text{ V} \le \text{V}_{CC} \le 5.5$	5 V	2.4		5.5	V
VIН	input logic nigh	-40 C S I _A S 65 C	V _{CC} = 4.5 V		2		5.5	
V_{IL}	Input logic low	$4.5 \text{ V} \le \text{V}_{\text{CC}} \le 5.5 \text{ V}, -40^{\circ}\text{C} \le \text{T}$	A ≤ 85°C		0		0.8	V
	Input leakage current	$V_1 = 5.5 \text{ V or } 0. \text{ V}_{CC} = 5.5 \text{ V}$		T _A = 25°C	-0.05		0.05	
I _{IH} , I _{IL}	input leakage current	V _I = 5.5 V Or U, V _{CC} = 5.5 V		-40°C ≤ T _A ≤ 85°C	-0.05		0.05	μA
DYNAMIC	;							
t	Turnon time	$V_{COM} = 3 \text{ V}, R_{L} = 300 \Omega, C_{L} =$	$V_{CC} = 5 \text{ V}, T_A = 2$	5 V, T _A = 25°C			9	ne
t _{ON}	rumon ume	35 pF, see Figure 9	4.5 V ≤ V _{CC} ≤ 5.5 V, −40°C ≤ T _A ≤ 85°C				10	ns

All unused digital inputs of the device must be held at V_{CC}or GND to ensure proper device operation. See *Implications of Slow or Floating CMOS Inputs* (SCBA004).



Electrical Characteristics: 5-V Supply (continued)

 $V_{CC} = 5 \text{ V}, T_A = 25^{\circ}\text{C} \text{ (unless otherwise noted)}$

PARAMETER		TES	TEST CONDITIONS		MIN	TYP	MAX	UNIT
	Turn off time	$V_{COM} = 3 \text{ V}, R_{L} = 300 \Omega, C_{L} =$	$V_{CC} = 5 \text{ V}, T_A = 25 \text{ V}$	°C			7	
t _{OFF}	Turnoff time	35 pF, see Figure 9	4.5 V ≤ V _{CC} ≤ 5.5 V	/, –40°C ≤ T _A ≤ 85°C			7.5	ns
	Drack hafara maka tima	$V_{NC} = V_{NO} = 3 \text{ V}, R_{L} = 300 \Omega, C$	C _L = 35 pF, see	T _A = 25°C	1			
t _{BBM}	Break-before-make time	Figure 10		-40°C ≤ T _A ≤ 85°C	0.9			ns
Q_C	Charge injection	$V_{GEN} = 0$, $R_{GEN} = 0$, $C_L = 1$ nF,	see Figure 14	·		12.5		рC
$\begin{array}{c} C_{NC(OFF)}, \\ C_{NO(OFF)} \end{array}$	NC, NO OFF capacitance	V_{NC} or $V_{NO} = V_{CC}$ or GND, $f = C$	V_{NC} or $V_{NO} = V_{CC}$ or GND, f = 1 MHz, Switch OFF, see Figure 8			3.5		pF
$\begin{matrix} C_{NC(ON)}, \\ C_{NO(ON)} \end{matrix}$	NC, NO ON capacitance	V_{NC} or $V_{NO} = V_{CC}$ or GND, $f = C$	V_{NC} or $V_{NO} = V_{CC}$ or GND, f = 1 MHz, see Figure 8			8.5		pF
C _{COM(ON)}	COM ON capacitance	V _{COM} = V _{CC} or GND, f = 1 MHz	, Switch ON, see Fig	ure 8		8.5		pF
Cı	Digital input capacitance	$V_I = V_{CC}$ or GND, $f = 1$ MHz, se	ee Figure 8			25		pF
BW	Bandwidth	$R_L = 50 \Omega$, Switch ON, see Figure 1	ure 11			100		MHz
O _{ISO}	OFF isolation	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MH$	z, Switch OFF, see F	igure 12		-84		dB
X _{TALK}	Crosstalk	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MH$	z, Switch ON, see Fi	gure 13		-85		dB
THD	Total harmonic distortion	$R_L = 600 \Omega$, $C_L = 50 pF$, $f = 20$	$R_L = 600 \Omega$, $C_L = 50 pF$, $f = 20 Hz$ to 20 kHz, see Figure 15			0.03%		
SUPPLY		·		<u> </u>			,	
	Positivo supply surrent	V V 0ND V 55V 0 11 0N 05	Switch ON or OFF	T _A = 25°C		0.01		
I _{CC}	Positive supply current	$v_1 = v_{CC}$ of GIND, $v_{CC} = 5.5 \text{ V}$,	$V_I = V_{CC}$ or GND, $V_{CC} = 5.5$ V, Switch ON or OFF	-40°C ≤ T _A ≤ 85°C			0.5	μA

6.6 Electrical Characteristics: 3-V Supply

 $V_{CC} = 3 \text{ V}, T_A = 25^{\circ}\text{C}$ (unless otherwise noted)

	PARAMETER	TE	ST CONDITIONS		MIN	TYP	MAX	UNIT
ANALOG	SWITCH	<u>'</u>		T.				
	ON state assistance	V_{NO} or $V_{NC} = 1.5 \text{ V}$, $V_{CC} = 2$.	7 V.	T _A = 25°C		11.5	15	
r _{ON}	ON-state resistance	$I_{COM} = -10$ mA, Switch ON, s		-40°C ≤ T _A ≤ 85°C			20	Ω
4-	ON-state resistance match	V_{NO} or $V_{NC} = 1.5 \text{ V}$, $V_{CC} = 2$.	7 V,	T _A = 25°C		0.05	0.3	Ω
∆r _{ON}	between channels	$I_{COM} = -10$ mA, Switch ON, s	see Figure 5	-40°C ≤ T _A ≤ 85°C			0.3	22
r _{ON(FLAT)}	ON-state resistance flatness	$0 \le (V_{NO} \text{ or } V_{NC}) \le V_{CC}, I_{COM}$	= -10 mA, Switch (ON, see Figure 5		2		Ω
I _{NC(OFF)} ,		V _{NC} or V _{NO} = 1 V and V _{COM} =		T _A = 25°C	-400		400	pА
I _{NO(OFF)}	NC, NO OFF leakage current	V_{NC} or $V_{NO} = 3$ V and $V_{COM} = V_{CC} = 3.3$ V, Switch OFF, se		-40°C ≤ T _A ≤ 85°C	-2		2	nA
I _{NC(ON)} ,		V _{NC} or V _{NO} = 1 V and V _{COM} =		T _A = 25°C	-400		400	pА
I _{NO(ON)}	NC, NO ON leakage current	V_{NC} or $V_{NO} = 3$ V and $V_{COM} = 3$ V; $V_{CC} = 3.3$ V, Switch ON, see Figure 7		-40°C ≤ T _A ≤ 85°C	-2		2	nA
	COM ON Inches a comment	V_{NC} or V_{NO} = Open, V_{COM} = 1 V or 3 V,		T _A = 25°C	-400		400	pА
I _{COM(ON)}	COM ON leakage current	$V_{CC} = 3.3 \text{ V, Switch ON, see}$	V _{CC} = 3.3 V, Switch ON, see Figure 7 -40°C ≤		-2		2	nA
DIGITAL I	INPUT (IN) ⁽¹⁾						·	
V _{IH}	Input logic high	-40°C ≤ T _A ≤ 85°C			2		5.5	V
V _{IL}	Input logic low	-40°C ≤ T _A ≤ 85°C			0		0.8	V
	Input leakage current	V _L = 5.5 V or 0, V _{CC} = 3.6 V		T _A = 25°C	-0.05		0.05	μA
I _{IH} , I _{IL}	input leakage current	v ₁ = 5.5 v or 0, v _{CC} = 5.6 v		$-40^{\circ}\text{C} \le \text{T}_{\text{A}} \le 85^{\circ}\text{C}$	-0.05		0.05	μΑ
DYNAMIC								
+	Turnon time	$V_{COM} = 3 \text{ V}, R_{L} = 300 \Omega,$	$V_{CC} = 3.3 \text{ V}, T_{A}$	_ = 25°C			13	ns
t _{ON}	rumon ume	C _L = 35 pF, see Figure 9	2.7 V ≤ V _{CC} ≤ 3.3 V, −40°C ≤ T _A ≤ 85°C				15	115
	Turnoff time	$V_{COM} = 3 \text{ V}, R_{L} = 300 \Omega,$	$= 300 \Omega$, $V_{CC} = 3.3 \text{ V}, T_A = 25^{\circ}\text{C}$				7.5	no
t _{OFF}	rumon ume	$C_L = 35 \text{ pF}$, see Figure 9 $2.7 \text{ V} \le V_{CC} \le 3.3 \text{ V}$, $-40^{\circ}\text{C} \le T_A \le 85^{\circ}\text{C}$				8.5	ns	
t	Break-before-make time	$V_{NC} = V_{NO} = 3 \text{ V}, R_{L} = 300 \Omega$, V _{CC} = 3.3 V,	T _A = 25°C	1			ne
t _{BBM}	Dieak-Deloie-make time	C _L = 35 pF, see Figure 10	·	-40 °C $\leq T_A \leq 85$ °C	0.9			ns
Q _C	Charge injection	$V_{GEN} = 0$, $R_{GEN} = 0$, $C_L = 1$ n	F, see Figure 14			6		рC

All unused digital inputs of the device must be held at V_{CC}or GND to ensure proper device operation. See *Implications of Slow or Floating CMOS Inputs* (SCBA004).



Electrical Characteristics: 3-V Supply (continued)

 $V_{CC} = 3 \text{ V}, T_A = 25^{\circ}\text{C}$ (unless otherwise noted)

	PARAMETER	TEST CONDITIONS		MIN TYP	MAX	UNIT
C _{NC (OFF)} , C _{NO(OFF)}	NC, NO OFF capacitance	V_{NC} or $V_{NO} = V_{CC}$ or GND, f = 1 MHz, Switch OFF, s	V_{NC} or $V_{NO} = V_{CC}$ or GND, f = 1 MHz, Switch OFF, see Figure 8			pF
C _{NC(ON)} , C _{NO(ON)}	NC, NO ON capacitance	V_{NC} or $V_{NO} = V_{CC}$ or GND, f = 1 MHz, Switch OFF, s	8.5		pF	
C _{COM(ON)}	COM ON capacitance	$V_{COM} = V_{CC}$ or GND, f = 1 MHz, Switch OFF, see Fig.	gure 8	8.5		рF
C _I	Digital input capacitance	V _I = V _{CC} or GND, f = 1 MHz, see Figure 8	V _I = V _{CC} or GND, f = 1 MHz, see Figure 8			рF
BW	Bandwidth	R_L = 50 Ω , Switch ON, see Figure 11	$R_L = 50 \Omega$, Switch ON, see Figure 11			MHz
O _{ISO}	OFF isolation	R_L = 50 Ω , f = 1 MHz, Switch OFF, see Figure 12	$R_L = 50 \Omega$, $f = 1 MHz$, Switch OFF, see Figure 12			dB
X _{TALK}	Crosstalk	R_L = 50 Ω , f = 1 MHz, Switch ON, see Figure 13		-85		dB
THD	Total harmonic distortion	R_L = 600 Ω , C_L = 50 pF, f = 20 Hz to 20 kHz, see Fig.	gure 15	0.09%		
SUPPLY					•	
	Positive supply current	$V_{I} = V_{CC}$ or GND, $V_{CC} = 3.6$ V, Switch ON or OFF	T _A = 25°C	0.01		
I _{CC}			-40°C ≤ T _A ≤ 85°C		0.5	μA

6.7 Electrical Characteristics: 2.5-V Supply

 $V_{CC} = 2.5 \text{ V}$. $T_A = 25^{\circ}\text{C}$ (unless otherwise noted)

	PARAMETER	TE	ST CONDITIONS		MIN	TYP	MAX	UNIT
ANALOG	SWITCH							
-	ON-state resistance	V_{NO} or $V_{NC} = 1 \text{ V}, V_{CC} = 2.25$	V,	T _A = 25°C		15	25	Ω
r _{ON}	ON-state resistance	$I_{COM} = -10$ mA, Switch ON, s	ee Figure 5	-40 °C $\leq T_A \leq 85$ °C			28	
Ar	ON-state resistance match	V_{NO} or $V_{NC} = 1 \text{ V}, V_{CC} = 2.25$	T _A = 25°C		0.06	0.3	Ω	
Δr _{ON}	between channels	$I_{COM} = -10$ mA, Switch ON, s	ee Figure 5	-40°C ≤ T _A ≤ 85°C			0.3	52
r _{ON(FLAT)}	ON-state resistance flatness		$0 \le (V_{NO} \text{ or } V_{NC}) \le V_{CC}, V_{CC} = 2.25 \text{ V},$ $I_{COM} = -10 \text{ mA}, \text{ Switch ON, see Figure 5}$			4		Ω
I _{NC(OFF)} , NC NO OFF leakage current		V_{NC} or $V_{NO} = 1.5 \text{ V}$ and V_{CON}		T _A = 25°C	-300		300	pΑ
I _{NO(OFF)}							1	nA
hioron		V_{NC} or V_{NO} = 1.5 V and V_{CON}		T _A = 25°C	-300		300	pA
I _{NC(ON)} , I _{NO(ON)}	NC, NO ON leakage current	V_{NC} or V_{NO} = 1.5 V and V_{COM} V_{CC} = 2.75 V, Switch ON, see	-40°C ≤ T _A ≤ 85°C	-1		1	nA	
	COM ON leakage current	V_{NC} or V_{NO} = Open, V_{COM} = 0		T _A = 25°C	-300		300	pΑ
I _{COM(ON)}	COW ON leakage current	$V_{CC} = 2.75 \text{ V}$, Switch ON, see	$V_{CC} = 2.75 \text{ V}$, Switch ON, see Figure 7				1	nA
DIGITAL I	NPUT (IN) ⁽¹⁾							
V_{IH}	Input logic high			-40°C ≤ T _A ≤ 85°C	2		5.5	V
V_{IL}	Input logic low			-40°C ≤ T _A ≤ 85°C	0		0.4	V
I _{IH} , I _{IL}	Input leakage current	V _I = 5.5 V or 0 V, V _{CC} = 2.75	V	$T_A = 25^{\circ}C$	-0.05		0.05	μA
'IH, 'IL	input leakage current	V = 0.5 V OI O V, VCC = 2.75		-40 °C $\leq T_A \leq 85$ °C	-0.05 0.0		0.05	μΛ
DYNAMIC								
		$V_{COM} = 2 \text{ V}, R_{I} = 300 \Omega,$	$V_{CC} = 2.5 \text{ V}, T_A = 2.5 \text{ V}$	25°C			18	
t _{ON}	Turnon time	C _L = 35 pF, see Figure 9	$2.25 \text{ V} \le \text{V}_{CC} \le 2.7$ $-40^{\circ}\text{C} \le \text{T}_{A} \le 85^{\circ}\text{C}$				20	ns
		$V_{COM} = 2 \text{ V}, R_L = 300 \ \Omega, \\ C_L = 35 \text{ pF, see Figure 9}$ $V_{CC} = 2.5 \text{ V}, T_A = 2$ $2.25 \text{ V} \le V_{CC} \le 2.7t$ $-40^{\circ}\text{C} \le T_A \le 85^{\circ}\text{C}$		25°C			8	
t _{OFF}	Turnoff time						9.5	ns
	Drack before make time	$V_{NC} = V_{NO} = 2 \text{ V}, R_{L} = 300 \Omega$, C _L = 35 pF, see	T _A = 25°C	1			
t _{BBM}	Break-before-make time	Figure 10		-40 °C $\leq T_A \leq 85$ °C	0.9			ns
Q _C	Charge injection	$V_{GEN} = 0, R_{GEN} = 0, C_L = 1 n$			4.5		рC	
C _{NC (OFF)} , C _{NO(OFF)}	NC, NO OFF capacitance	V_{NC} or $V_{NO} = V_{CC}$ or GND, f =	V _{NC} or V _{NO} = V _{CC} or GND, f = 1 MHz, Switch OFF, see Figure 8					pF
C _{NC(ON)} , C _{NO(ON)}	NC, NO ON capacitance	V _{NC} or V _{NO} = V _{CC} or GND, f =	1 MHz, Switch OFF,	see Figure 8		8.5		pF

All unused digital inputs of the device must be held at V_{CC}or GND to ensure proper device operation. See *Implications of Slow or Floating CMOS Inputs* (SCBA004).

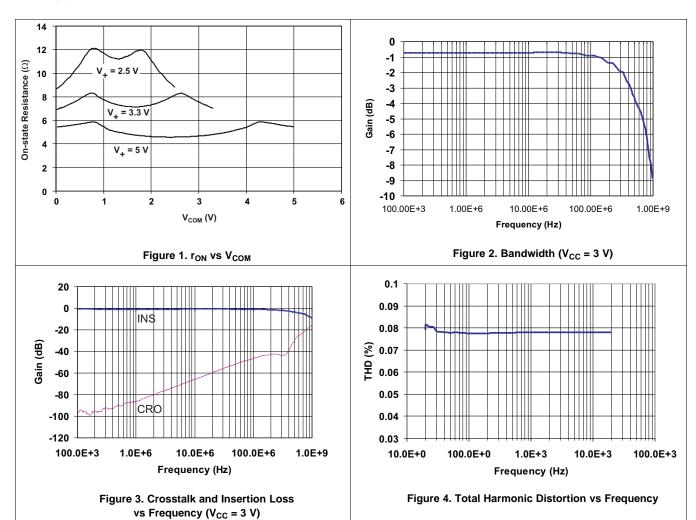


Electrical Characteristics: 2.5-V Supply (continued)

 $V_{CC} = 2.5 \text{ V}, T_A = 25^{\circ}\text{C} \text{ (unless otherwise noted)}$

	PARAMETER	TEST CONDITIONS	MIN TYP	MAX	UNIT			
C _{COM(ON)}	COM ON capacitance	$V_{COM} = V_{CC}$ or GND, f = 1 MHz, Switch OFF, see Fig.	8.5		pF			
Ci	Digital input capacitance	V _I = V _{CC} or GND, f = 1 MHz, see Figure 8	V _I = V _{CC} or GND, f = 1 MHz, see Figure 8					
BW	Bandwidth	$R_L = 50 \Omega$, Switch ON, see Figure 11	$R_L = 50 \Omega$, Switch ON, see Figure 11					
O _{ISO}	OFF isolation	$R_L = 50 \Omega$, f = 1 MHz, Switch OFF, see Figure 12	$R_L = 50 \Omega$, f = 1 MHz, Switch OFF, see Figure 12					
X _{TALK}	Crosstalk	$R_L = 50 \Omega$, f = 1 MHz, Switch ON, see Figure 13	$R_L = 50 \Omega$, f = 1 MHz, Switch ON, see Figure 13					
THD	Total harmonic distortion	0.15%						
SUPPLY								
	Desitive cumply current	V V or CND V 2.75 V Switch ON or OFF	T _A = 25°C	0.01				
Icc	Positive supply current	$V_I = V_{CC}$ or GND, $V_{CC} = 2.75$ V, Switch ON or OFF	-40°C ≤ T _A ≤ 85°C		0.5	μA		

6.8 Typical Characteristics



Submit Documentation Feedback
Product Folder Links: TS5A9411



7 Parameter Measurement Information

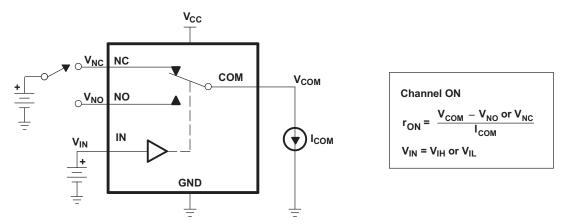
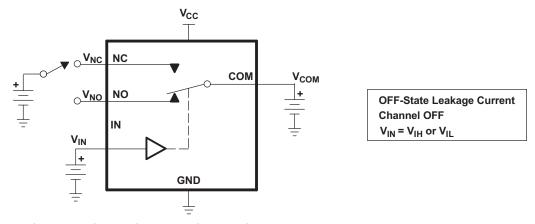


Figure 5. ON-State Resistance



 $I_{NC(OFF)},\ I_{NC(PWROFF)},\ I_{NO(OFF)},\ I_{NO(PWROFF)},\ I_{COM(OFF)},\ I_{COM(PWROFF)}$

Figure 6. OFF-State Leakage Current

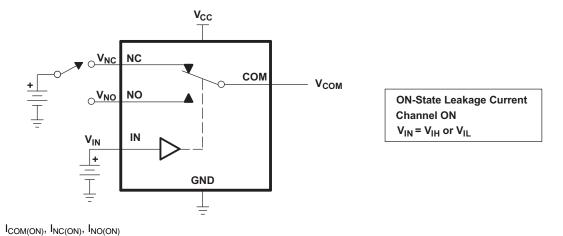
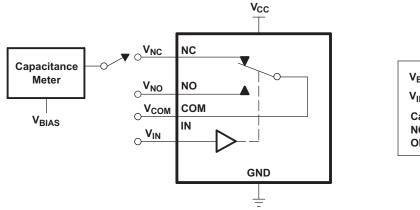


Figure 7. ON-State Leakage Current



Parameter Measurement Information (continued)



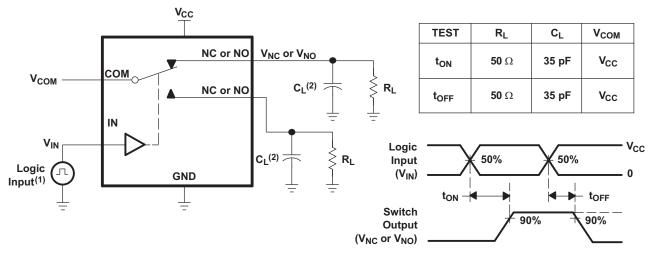
 $V_{BIAS} = V_{CC}$ or GND

 $V_{IN} = V_{CC}$ or GND

Capacitance is measured at NC, NO, COM, and IN inputs during ON and OFF conditions.

 $C_{\mathsf{I}},\,C_{\mathsf{COM}(\mathsf{ON})},\,C_{\mathsf{NC}(\mathsf{OFF})},\,C_{\mathsf{NO}(\mathsf{OFF})},\,C_{\mathsf{NC}(\mathsf{ON})},\,C_{\mathsf{NO}(\mathsf{ON})}$

Figure 8. Capacitance

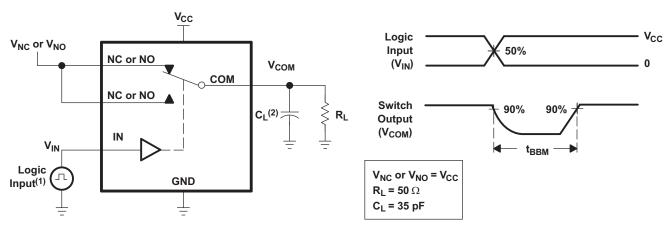


- (1) All input pulses are supplied by generators having the following characteristics:
 - PRR ≤ 10 MHz
 - $Z_O = 50 \Omega$
 - t_r < 5 ns
 - $t_f < 5 \text{ ns}$
- (2) C_L includes probe and jig capacitance.

Figure 9. Turnon and Turnoff Time



Parameter Measurement Information (continued)



- (1) All input pulses are supplied by generators having the following characteristics:
 - PRR ≤ 10 MHz
 - $Z_{\Omega} = 50 \Omega$
 - $t_r < 5 \text{ ns}$
 - $t_f < 5 \text{ ns}$
- (2) C_L includes probe and jig capacitance.

Figure 10. Break-Before-Make Time

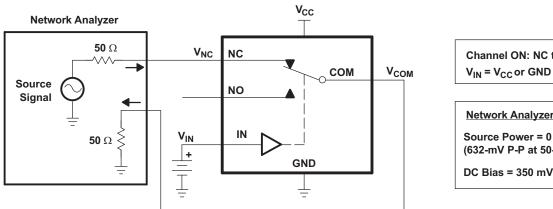


Figure 11. Bandwidth

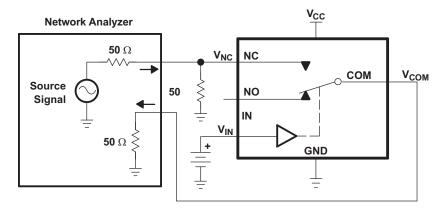


Figure 12. OFF Isolation

Channel ON: NC to COM $V_{IN} = V_{CC}$ or GND

Network Analyzer Setup

Source Power = 0 dBm (632-mV P-P at 50-Ω load)

Channel OFF: NC to COM $V_{IN} = V_{CC}$ or GND

Network Analyzer Setup

Source Power = 0 dBm (632-mV P-P at 50- Ω load) DC Bias = 350 mV



Parameter Measurement Information (continued)

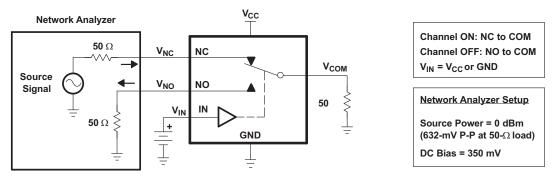
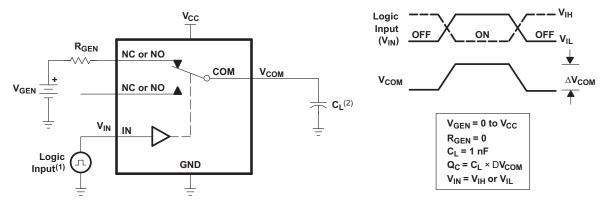
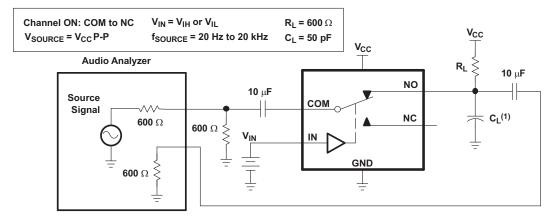


Figure 13. Crosstalk



- (1) All input pulses are supplied by generators having the following characteristics:
 - PRR ≤ 10 MHz
 - $Z_O = 50 \Omega$
 - t_r < 5 ns
 - t_f < 5 ns
- (2) C_L includes probe and jig capacitance.

Figure 14. Charge Injection



(1) C_L includes probe and jig capacitance.

Figure 15. Total Harmonic Distortion

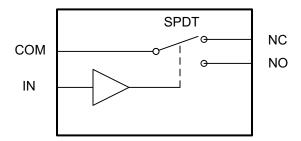


8 Detailed Description

8.1 Overview

The TS5A9411 device is a 1:2 or single-pole-double-throw (SPDT) solid-state analog switch. The TS5A9411, like all analog switches, is bidirectional. When powered on, each COM pin is connected to the NC pin or NO pin depending on the status of the IN pin. If IN is low, COM is connected to NC. If IN is high, COM is connected to NO. The TS5A9411 is a break-before-make switch. This means that during switching, a connection is broken before a new connection is established. The NC and NO pins are never connected to each other.

8.2 Functional Block Diagram



8.3 Feature Description

The low ON-state resistance, ON-state resistance matching, and charge injection in the TS5A9411 make this switch an excellent choice for analog signals that require minimal distortion. The 2.25-V to 5.5-V operation allows compatibility with more voltage nodes, and the bidirectional I/Os can pass analog signals from 0 V to V_{CC} with low distortion.

8.4 Device Functional Modes

Table 1 lists the functional modes of the TS5A9411. If IN pin is low, COM is connected to NC. If IN is high, COM is connected to NO.

Table 1. Function Table

IN	NC TO COM, COM TO NC	NO TO COM, COM TO NO
L	ON	OFF
Н	OFF	ON



9 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

9.1 Application Information

The switches are bidirectional, so the NO, NC, and COM pins can be used as either inputs or outputs. The device is used in systems where multiple analog or digital signals must be selected to pass across a single line.

9.2 Typical Application

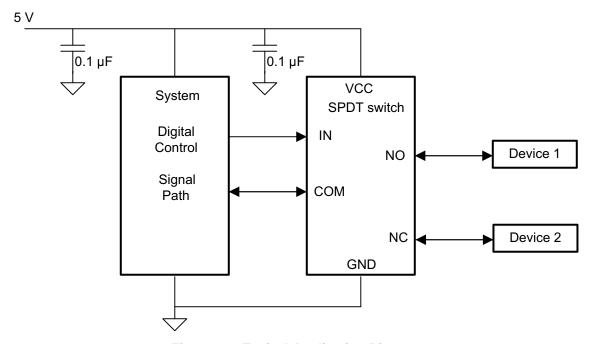


Figure 16. Typical Application Diagram

9.2.1 Design Requirements

Pull the digitally controlled input select pin (IN) to V_{CC} or GND to avoid unwanted switch states that could result if the logic control pin is left floating.

9.2.2 Detailed Design Procedure

Select the appropriate supply voltage to cover the entire voltage swing of the signal passing through the switch because the input or output signal swing of the device is dependant of the supply voltage (V_{CC}) .

Typical Application (continued)

9.2.3 Application Curve

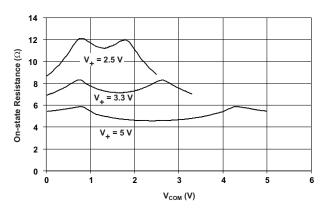


Figure 17. ron vs V_{COM}

10 Power Supply Recommendations

Proper power-supply sequencing is recommended for all CMOS devices. Do not exceed the absolute maximum ratings, because stresses beyond the listed ratings can cause permanent damage to the device. Always sequence VCC on first, followed by NO, NC, or COM pins.

Although it is not required, power-supply bypassing improves noise margin and prevents switching noise propagation from the V_{CC} supply to other components. A 0.1- μF capacitor, connected from VCC to GND, is adequate for most applications.

11 Layout

11.1 Layout Guidelines

TI recommends placing a bypass capacitor as close to the supply pins (VCC and –VCC) as possible to help smooth out lower frequency noise to provide better load regulation across the frequency spectrum. Minimize trace lengths and vias on the signal paths to preserve signal integrity.

11.2 Layout Example

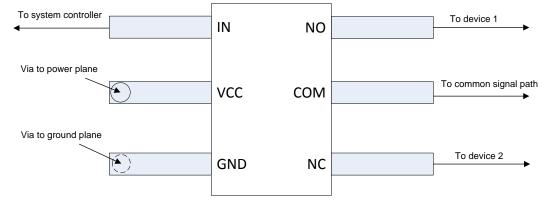


Figure 18. Layout Recommendation



12 Device and Documentation Support

12.1 Device Support

12.1.1 Device Nomenclature

BW Bandwidth of the switch. This is the frequency in which the gain of an ON channel is -3 dB below

the DC gain.

C_{COM(ON)} Capacitance at the COM port when the corresponding channel (COM to NC or COM to NO) is ON.

C_{NC(OFF)} Capacitance at the NC port when the corresponding channel (NC to COM) is OFF.

C_{NC(ON)} Capacitance at the NC port when the corresponding channel (NC to COM) is ON.

C_{NO(OFF)} Capacitance at the NO port when the corresponding channel (NO to COM) is OFF.

C_{NO(ON)} Capacitance at the NO port when the corresponding channel (NO to COM) is ON.

C_I Capacitance of control input (IN).

 I_{CC} Static power-supply current with the control (IN) pin at V_{CC} or GND.

I_{COM(ON)} Leakage current measured at the COM port, with the corresponding channel (COM to NO or COM

to NC) in the ON state and the output (NC or NO) open.

 $I_{COM(PWROFF)}$ Leakage current measured at the COM port during the power-down condition ($V_{CC} = 0$).

I_{IH}, I_{IL} Leakage current measured at the control input (IN).

I_{NC(OFF)} Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the OFF

state under worst-case input and output conditions.

I_{NC(ON)} Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the ON

state and the output (COM) open.

I_{NO(OFF)} Leakage current measured at the NO port, with the corresponding channel (NO to COM) in the

OFF state under worst-case input and output conditions.

I_{NO(ON)} Leakage current measured at the NO port, with the corresponding channel (NO to COM) in the ON

state and the output (COM) open.

O_{ISO} OFF isolation of the switch is a measurement of OFF-state switch impedance. This is measured in

dB in a specific frequency, with the corresponding channel (NC to COM or NO to COM) in the OFF

state.

Q_c Charge injection is a measurement of unwanted signal coupling from the control (IN) input to the

analog (NC, NO, or COM) output. This is measured in coulomb (C) and measured by the total charge induced due to switching of the control input. Charge injection, $Q_C = C_L \times \Delta V_{COM}$, C_L is the

load capacitance and ΔV_{COM} is the change in analog output voltage.

 Δr_{ON} Difference of r_{ON} between channels in a specific device.

r_{ON} Resistance between COM and NC or COM and NO ports when the channel is ON.

r_{ON(FLAT)} Difference of r_{ON} in a channel over the specified range of conditions.

t_{BBM} Break-before-make time. This parameter is measured under the specified range of conditions and

by the propagation delay between the output of two adjacent analog channels (NC and NO) when

the control signal changes state.

t_{OFF} Turnoff time for the switch. This parameter is measured under the specified range of conditions and

by the propagation delay between the digital control (IN) signal and analog output (COM, NC, or

NO) signal when the switch is turning OFF.

 t_{ON} Turnon time for the switch. This parameter is measured under the specified range of conditions and

by the propagation delay between the digital control (IN) signal and analog output (COM, NC, or

NO) signal when the switch is turning ON.

THD Total harmonic distortion describes the signal distortion caused by the analog switch. This is



Device Support (continued)

defined as the ratio of root mean square (RMS) value of the second, third, and higher harmonic to the absolute magnitude of the fundamental harmonic.

V_{COM} Voltage at COM.

V_I Voltage at the control input (IN).

V_{IH} Minimum input voltage for logic high for the control input (IN).

V_{IL} Maximum input voltage for logic low for the control input (IN).

V_{NC} Voltage at NC.V_{NO} Voltage at NO.

X_{TALK} Crosstalk is a measurement of unwanted signal coupling from an ON channel to an OFF channel

(NC to NO or NO to NC). This is measured in a specific frequency and in dB.

12.2 Documentation Support

12.2.1 Related Documentation

For related documentation see the following:

Implications of Slow or Floating CMOS Inputs (SCBA004)

12.3 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

12.4 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community *TI's Engineer-to-Engineer (E2E) Community.* Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

12.5 Trademarks

E2E is a trademark of Texas Instruments.

All other trademarks are the property of their respective owners.

12.6 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

12.7 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.



13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

www.ti.com 14-May-2025

PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/	MSL rating/	Op temp (°C)	Part marking
	(1)	(2)			(3)	Ball material	Peak reflow		(6)
						(4)	(5)		
TS5A9411DCKR	Active	Production	SC70 (DCK) 6	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	(32F, 32R) (32H, 32P)
TS5A9411DCKR.Z	Active	Production	SC70 (DCK) 6	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	(32F, 32R) (32H, 32P)
TS5A9411DCKRG4.Z	Active	Production	SC70 (DCK) 6	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	(32F, 32R) (32H, 32P)
TS5A9411DCKT	Obsolete	Production	SC70 (DCK) 6	-	-	Call TI	Call TI	-40 to 85	(32F, 32R) 32H

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.



PACKAGE OPTION ADDENDUM

www.ti.com 14-May-2025

PACKAGE MATERIALS INFORMATION

www.ti.com 14-Dec-2024

TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

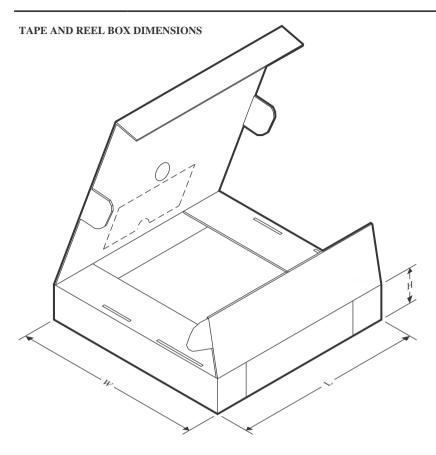


*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TS5A9411DCKR	SC70	DCK	6	3000	180.0	8.4	2.41	2.41	1.2	4.0	8.0	Q3

PACKAGE MATERIALS INFORMATION

www.ti.com 14-Dec-2024

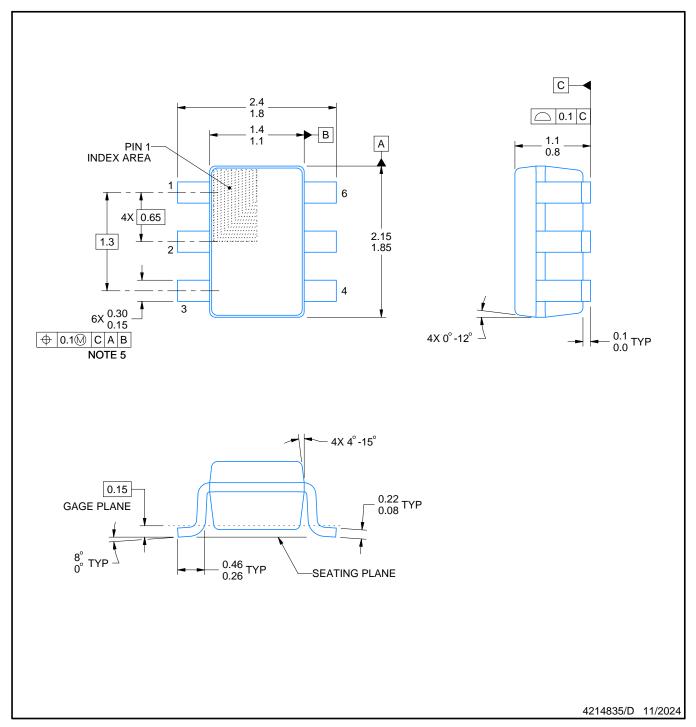


*All dimensions are nominal

Г	Device	Package Type	Package Drawing	kage Drawing Pins		Length (mm)	Width (mm)	Height (mm)	
	TS5A9411DCKR	SC70	DCK	6	3000	202.0	201.0	28.0	



SMALL OUTLINE TRANSISTOR



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

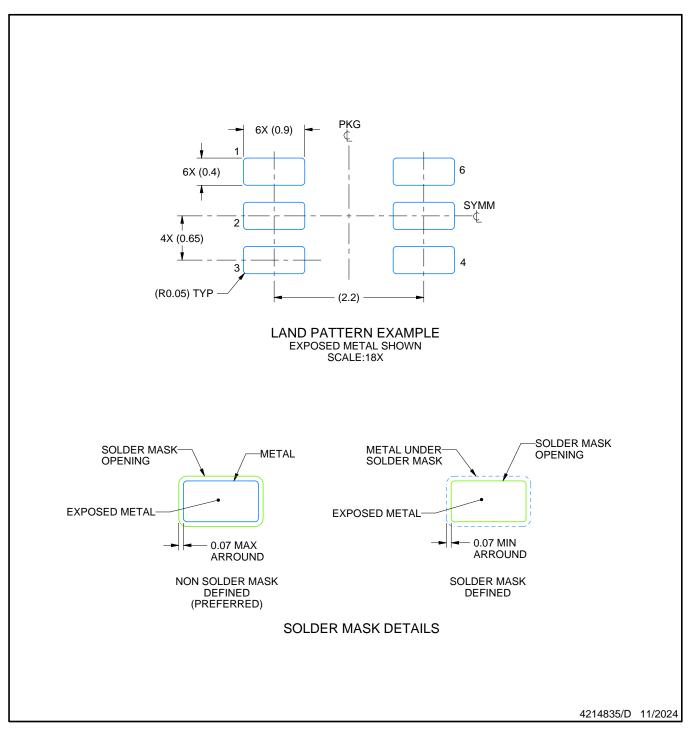
 2. This drawing is subject to change without notice.

 3. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.

 4. Falls within JEDEC MO-203 variation AB.



SMALL OUTLINE TRANSISTOR



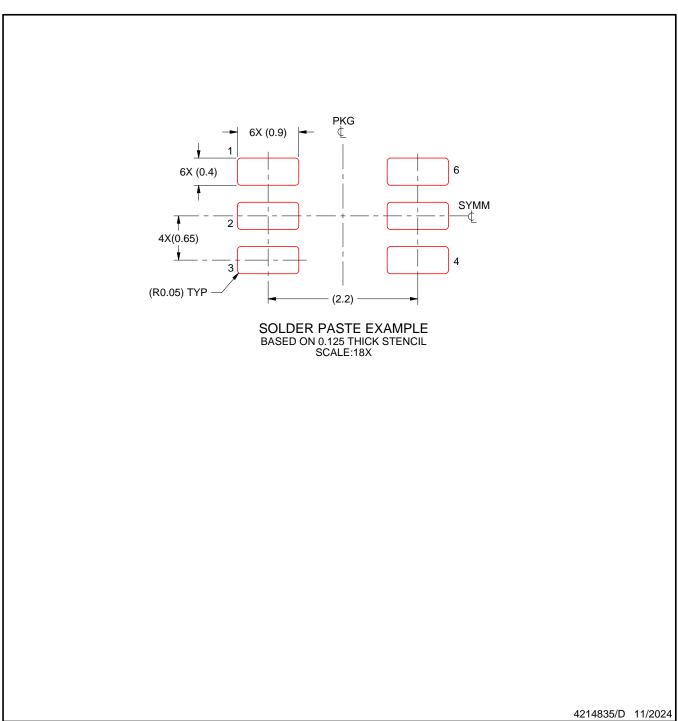
NOTES: (continued)

5. Publication IPC-7351 may have alternate designs.

6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE TRANSISTOR



NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.



IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATA SHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

TI objects to and rejects any additional or different terms you may have proposed.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2025. Texas Instruments Incorporated